Real-Time Machine Learning

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Deadline for manuscript
submissions:
closed (30 June 2021)

Message from the Guest Editors

The purpose of this Special Issue is to present original work that provides insight into how machine learning is most effectively integrated into resource-constrained computing architectures. We solicit topics from all areas of real-time machine learning, including, but not limited to, training and deployment of machine learning models on real-time systems, modeling energy efficiency of machine learning algorithms, hardware-based machine learning models, real-time software and hardware architectures for machine learning, and novel applications of machine learning designed for embedded, real-time environments.

Keywords

- real-time machine learning
- machine learning hardware architectures
- embedded machine learning applications
- embedded machine learning algorithms
- energy efficient machine learning
- resource-constrained machine learning

mdpi.com/si/39392

Special Issue

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Message from the Editor-in-Chief

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